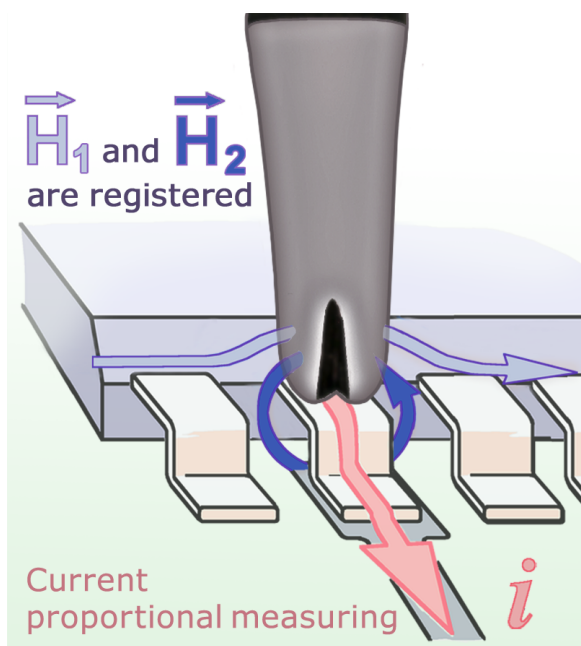


# XF-U 2.5-1

H-Field Probe 30 MHz up to 6 GHz



## Short description

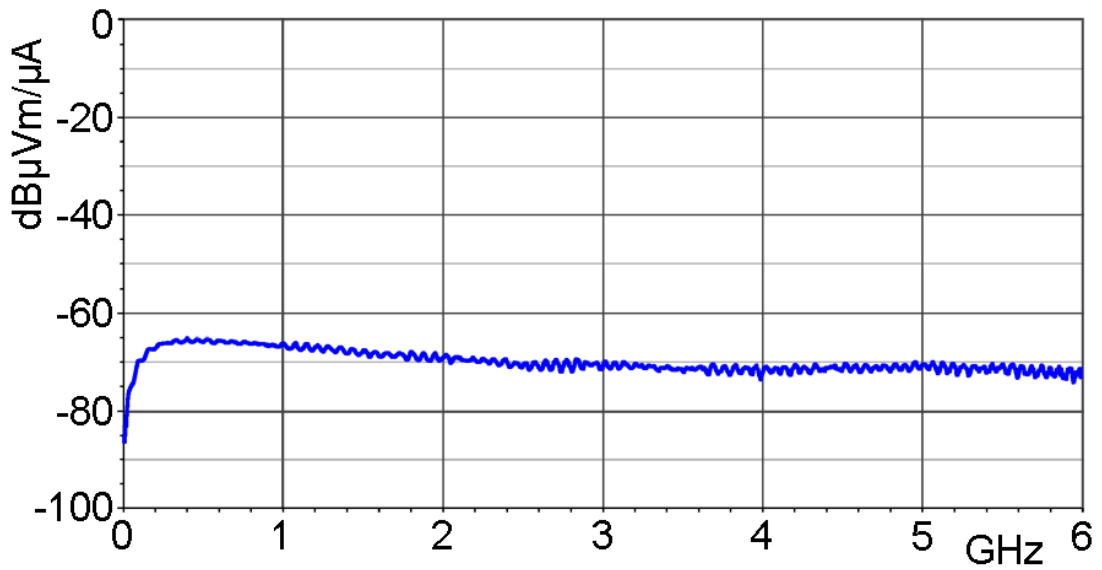
The XF-U 2.5-2 near-field probe is designed for the selective measurements of RF currents in conducting paths, component connectors, SMD components, and IC pins. The probe head has a magnetically active gap with an approx. width of 0.5 mm. To use, the head should be positioned directly onto the measured object.

The XF-U 2.5-2 is a passive near-field probe that is designed for SMD components (pins). The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50  $\Omega$  input. The H-field probe has an internal terminating resistance.

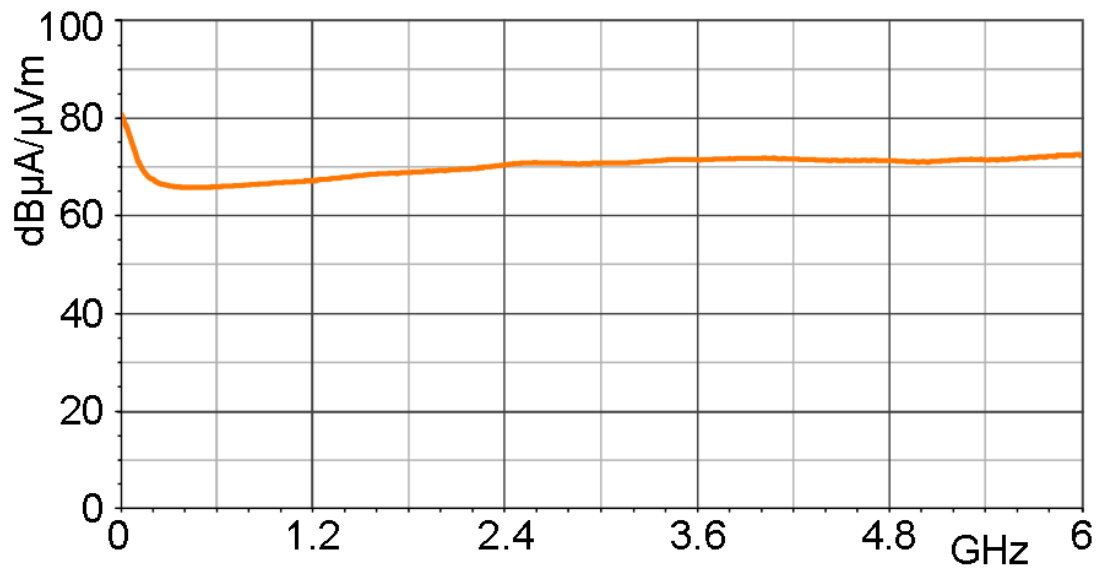
## Technical parameters

|                       |                            |
|-----------------------|----------------------------|
| Frequency range       | 30 MHz ... 6 GHz           |
| Resolution            | $\approx 0.5$ mm           |
| Probe head dimensions | $\varnothing \approx 4$ mm |
| Connector - output    | SMA, female, jack          |
| Weight                | 15 g                       |

Frequency response [dB $\mu$ V] / [dB $\mu$ A/m]



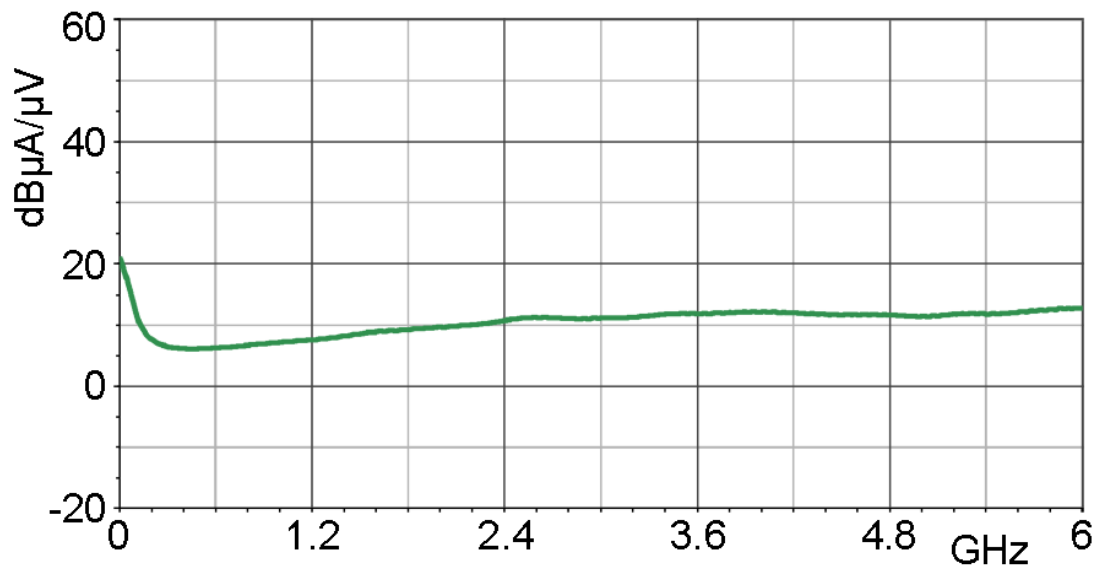
H-field correction curve [dB $\mu$ A/m] / [dB $\mu$ V]



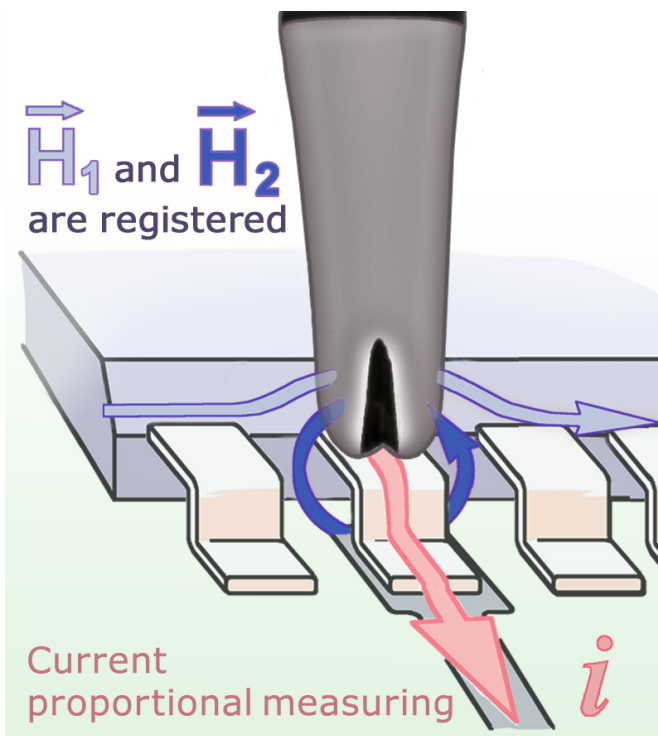
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Current correction curve [dB $\mu$ A] / [dB $\mu$ V]



Measuring principles



# XF-U 2.5-1

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Probe head

